

A Digital Silicon Photomultiplier

The Circuit, and its Characterization

Inge Diehl, <u>Finn Feindt</u>, Karsten Hansen, Stephan Lachnit, Frauke Poblotzki, Daniil Rastorguev, Simon Spannagel, Tomas Vanat, and Gianpiero Vignola

13th International "Hiroshima" Symposium on the Development and Application of Semiconductor Tracking Detectors December 8, 2023 Vancouver, Canada





Motivation

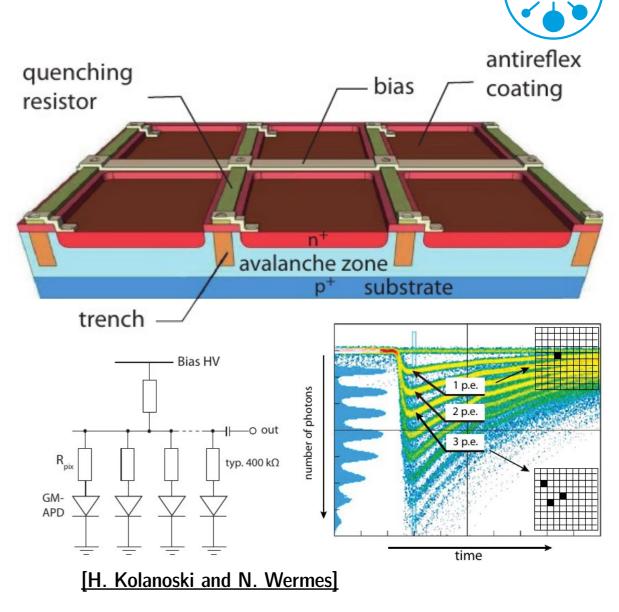
For Digital SiPMs



Silicon Photomultipliers

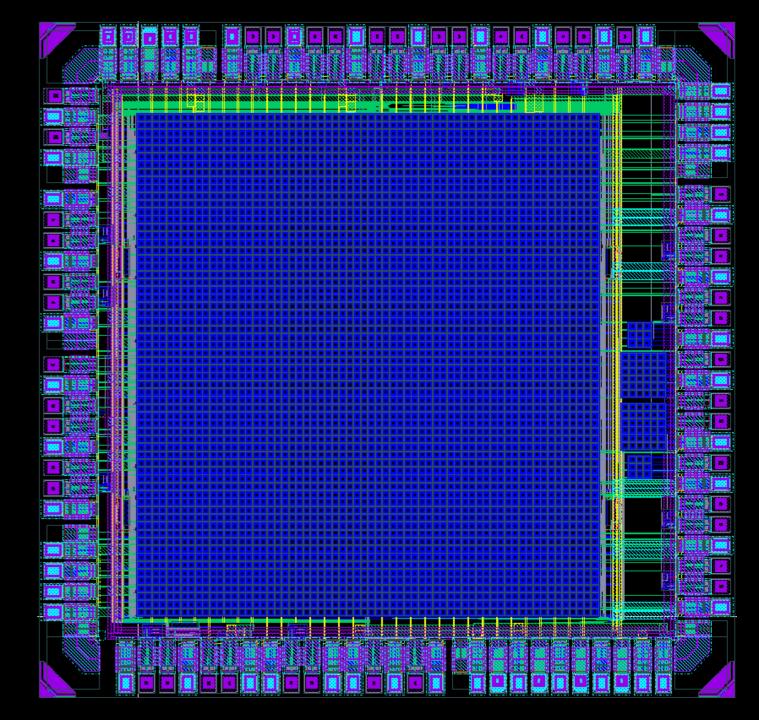
Digital Devices with Analog Digital Readout

- Array of SPADs (Single-Photon Avalanche Diodes), sizes between 15 and 70 um
- Single photon detection efficiencies reach O(50 %)
- Fast peaking time, reaching time resolutions of few 10 ps
- Typically with analog readout of all SPADs in parallel
- More light: number of firing SPADs approx. proportional to photon flux (within some constrains)
- BUT: The information a single SPAD provides is DIGITAL
- Add CMOS circuitry
 - No loss of information by digitizing SPAD signals
 - Profit from digital signal processing
 - E.g. resolve position of firing SPADs



The Circuit

A Digital Silicon Photomultiplier – Designed in LFoundry's 150-nm CMOS



The Readout Scheme

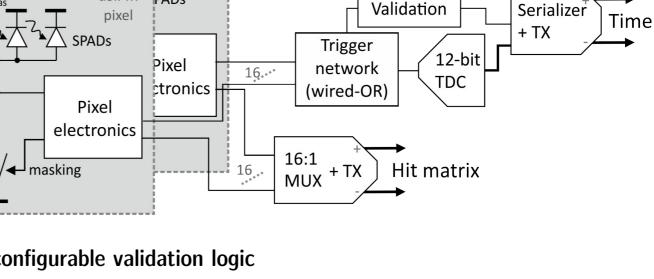
Key Components

- Four SPADs make a pixel
 - Variable quenching resistance (V_{quench})
 - Masking (pixel not powered)
 - 2-bit hit counter (2 readout modes)
 - Wired-or connection to quadrant TDC
- 16x16 pixels form quadrant unit with
 - 12-bit TDC, time stamps of 1st firing pixel per frame; configurable validation logic
 - Per-frame hit-matrix readout
 - This looks like a pixel detector! <u>Can we operate it like a pixel detector?</u>

V_{Quench}

16 x 16

- What are its MIP detection properties? Efficiency? Spatial and temporal resolution?
- Are 4D tracking applications feasable?



dSiPM

pixel

PADs

dSiPM

40-bit frame

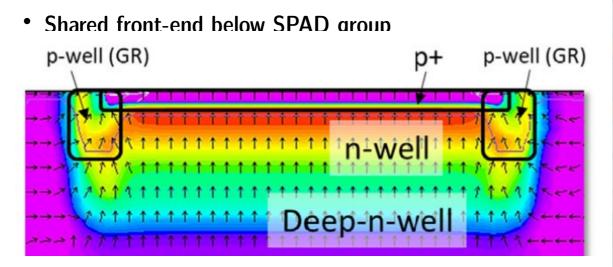
counter



The Pixel

Four SPADs Make a Pixel

- Four library p+/n-well SPADs, 20 x 20 um², in parallel
- Surrounded by cathode and p-well ring for cross-talk minimization
- Pixel area 69.6 x 76 μ um², fill factor 30 %



Example of a p+/n-well SPAD in a CMOS process [F. Acerbi and S. Gundacker]

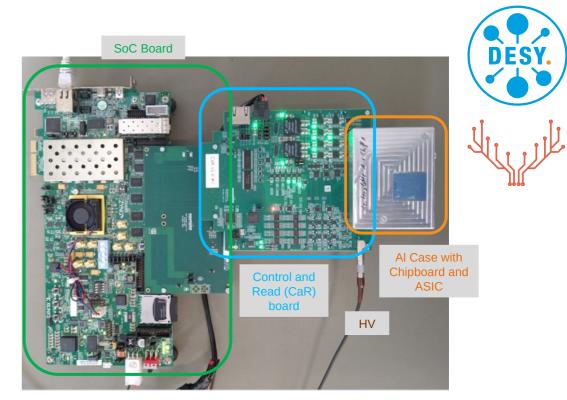




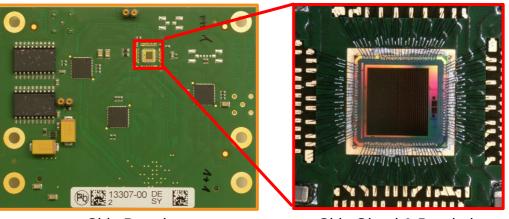
Caribou

A Versatile Readout System

- Developed by CERN, BNL, and DESY
- Fast, simple and low-cost implementation & tests of sensors, already 16 devices e.g. ATLASPix, CLICTD, ...
- System on Chip (SoC) Board CPU and FPGA on same die
 - A CPU runs DAQ and control software
 - An FPGA runs custom hardware for data handling and detector control
- Control and Readout (CaR) Interface Board
 - Physical interface from the SoC to the sensor
 - Peripherals needed to interface and run the chip: power supplies, ADCs, voltage/current references, LVDS links, etc.
- Chip Board passive & detector-specific components





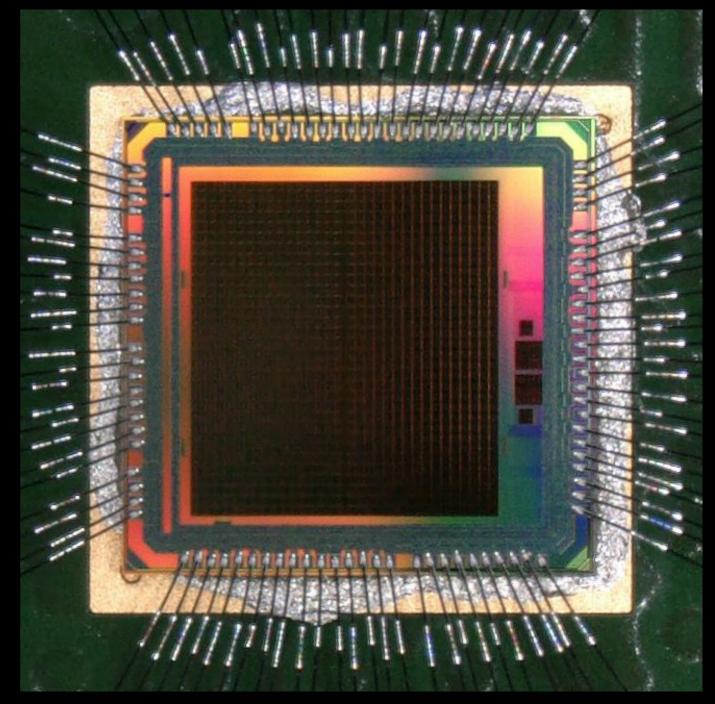


Chip Board

Chip Glued & Bonded

Characterization

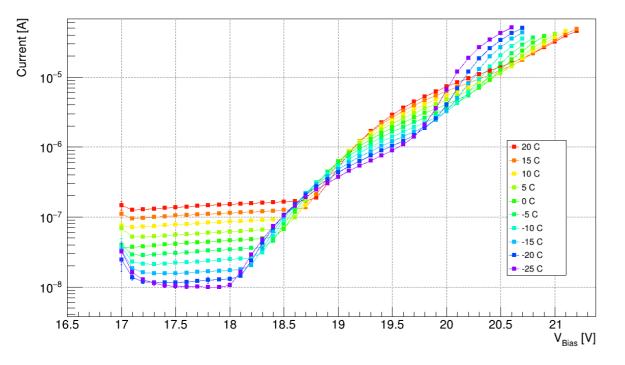
Laboratory



Lab – IV and Breakdown Voltage

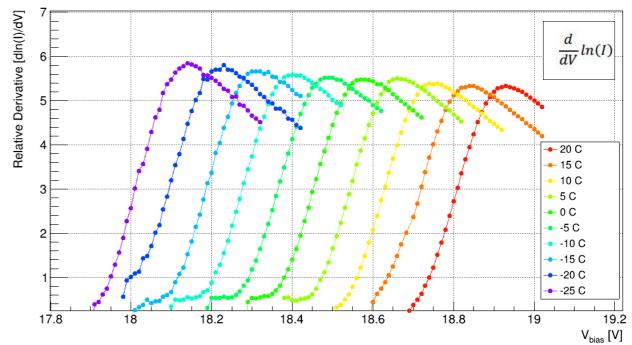
Because Breakdown is what we Need

- Scanning the bias voltage in the breakdown region
- Different temperatures (climate chamber, humidity \sim 0%)
- Shift of breakdown voltage with temperature visible
- Avoid secondary breakdown for operation





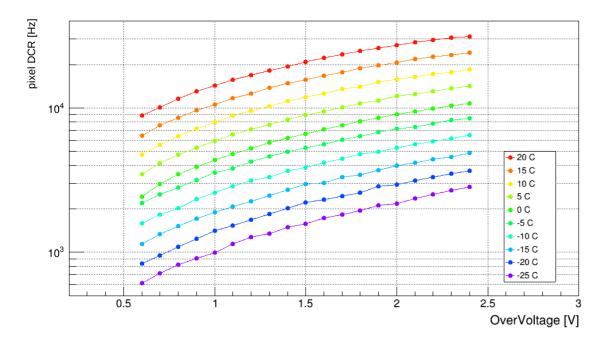
- Various definitions of breakdown voltage around
- We used the "relative derivative"
- Measured breakdown as a function of temperature
- * 18.9 V at 20°C and about 20 mV/K



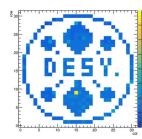
Lab – DCR

Dark Count Rate

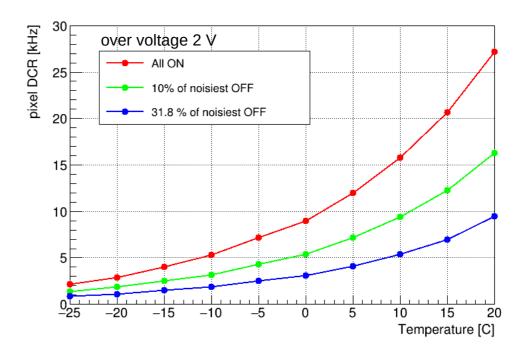
- Reading frames in dark environment
- Strong dependence on temperature and over voltage
 - Cooling helps!
- 10⁴ Hz per pixel corresponds to $6.25 \text{ Hz}/\text{um}^2$



Thermal excitation \rightarrow carriers \rightarrow discharge



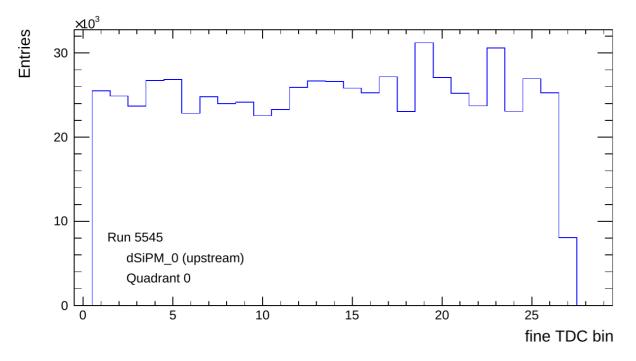
- Pixel masking helps!
- * Masking noisiest 10 % reduces noise by about 40 %
- Observed also an impact on leakage current
 - Interesting case: single pixel determines breakdown



TDC Characterization

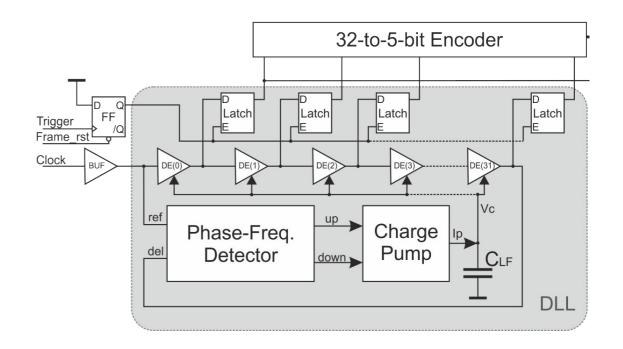
Measuring TDC Bin-Width Variations

- Studying the fine TDC with nominal binning of 77 ps
- Expecting constant occupancy (on short time scale)
- Variations are due to delay variations
- Not exploiting full dynamic range of 32 bins!





- Find corrections statistical code density analysis
- The width of a bin corresponds to its fraction of the total entries times the clock period (\sim 2.5 ns)
- Mean bin width 93.1 ps

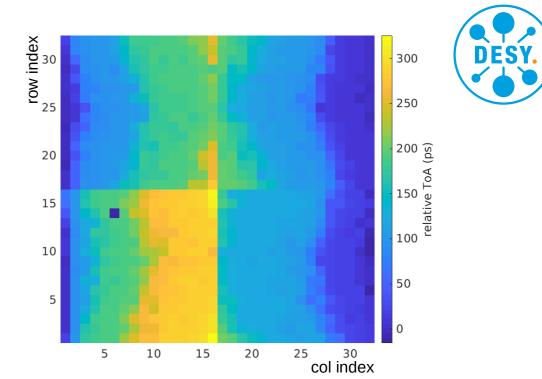


Laser Measurements

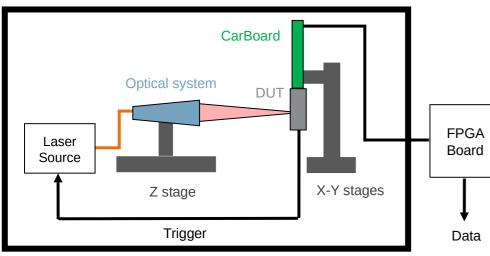
Measuring Propagation Delays

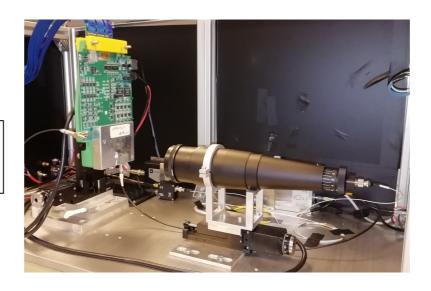
Setup

- DUT placed on an x-y stage; laser optical system on a z-stage
- * 1054 nm pulsed laser; focus width < 10 um in beam waist
- Laser in sync. with the DAQ clock
- Scan chip pixel-by-pixel, measure Time of Arrival (ToA)









- Clear function of distance to TDC
- Different offsets for each quadrant

Characterization Beam Tests



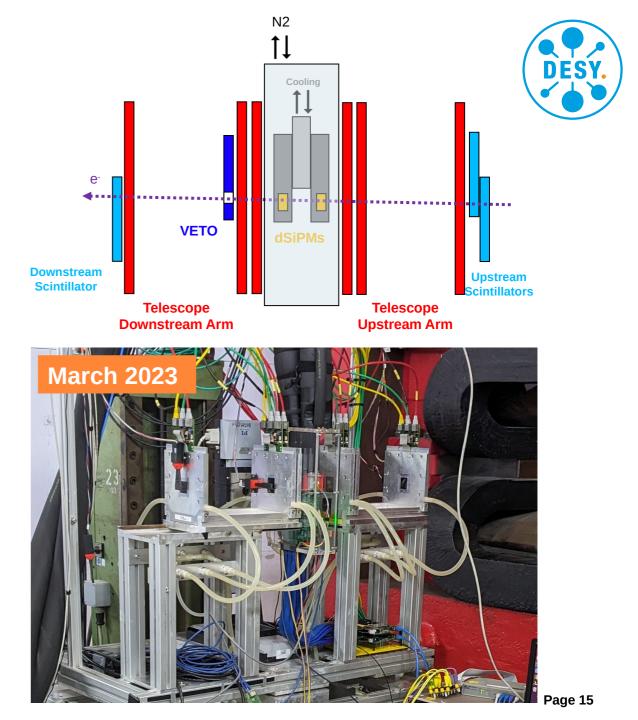
reddit.com/r/ScientificArt/

Our Setup

Evolving...

Setup in March 2023

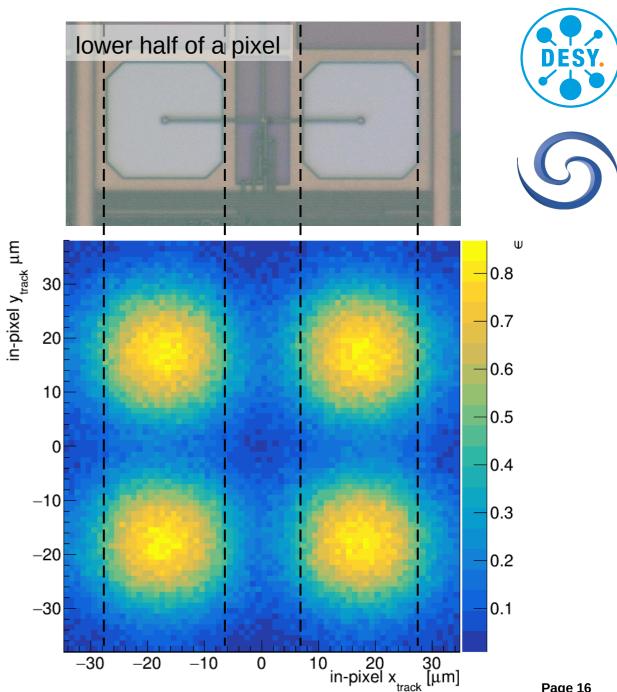
- Main goal: measure time resolution
- Triggering using 3 scintillators in coincidence
 - 4th scintillator with hole vetoes tracks out of acceptance
- For the time resolution measurement we take 2 dSiPMs
 - Not easy to find time reference better than 100 ps
 - Assume 2 DUTs have similar resolution
 - Derive residual $\Delta t = t_{_{DUT1}} t_{_{DUT2}}$
 - + DUT resolution $\sigma_{_{DUT}}=\sigma_{_{\Delta t}}$ / $\surd 2$
- Custom cold box to allow for temperatures down to -5°C
- Estimated track resolution around 4 um



Hit Detection Efficiency

Fill Factor Limited

- Analysis using <u>Corryvreckan</u>
 - Reconstruct tracks using the beam telescope
 - Associate hits on DUT using spatial cuts
 - $\mathbf{E} = \mathbf{N}_{assoc} / \mathbf{N}_{reco}$
- In-pixel efficiency
 - Inefficient outside of SPAD region
 - Smearing due to track resolution (larger than expected)
- Over all efficiency determined by fill factor ٠
 - About 30 %, corrected for dead time and fake hit contributions
 - Small voltage dependence above breakdown observed

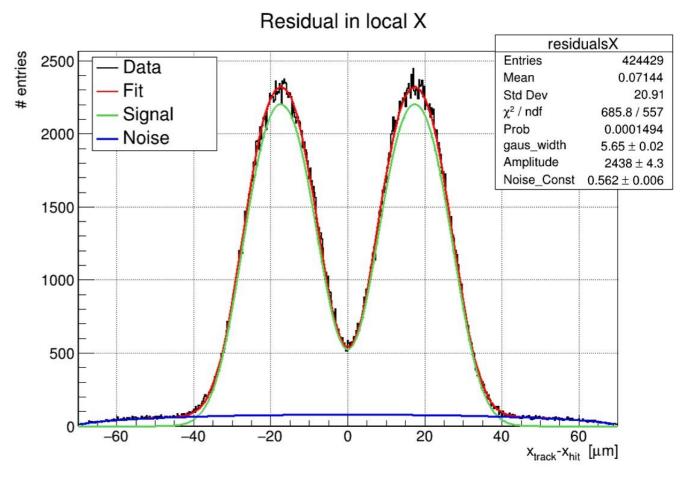


Spatial Resolution

Determined by Pixel Size

- Difference between reconstructed hit and interpolated track position $\Delta x = x_{\text{track}}$ x_{hit}
- Double peak feature due to in-efficient region between SPADs (remember previous slide!)
 - Added Corryvreackan feature: Define arbitrary fit function for DUT alignment <u>MR</u>
- Unavoidable contribution from dark counts (circular background distribution)
- Signal described by double box convolved with Gaussian
- Does the track resolution explain the width of the Gaussian?
- Achieve spatial resolution on the order of 20 um



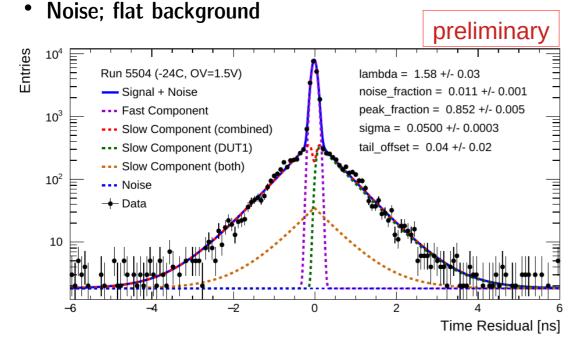


Time Residuals

Measuring the Time Resolution

Time residual between two dSiPMs $\Delta t = t_{_{DUT1}} - t_{_{DUT2}}$

- Each of them contributes 3 cases
 - Fast signal; Gaussian with width between 35 and 55 ps
 - Slow signal; exponential tail (about 15 %)





Time Residuals

Measuring the Time Resolution

Time residual between dSiPM and ref. $\Delta t = t_{_{DUT0}} - t_{_{TLU}}$

- Fast signal; dominated by time reference
 - Trigger scintillator + TDC in AIDA TLU
- Slow signal; slow DUT response



180

160

140

120

100

80

60

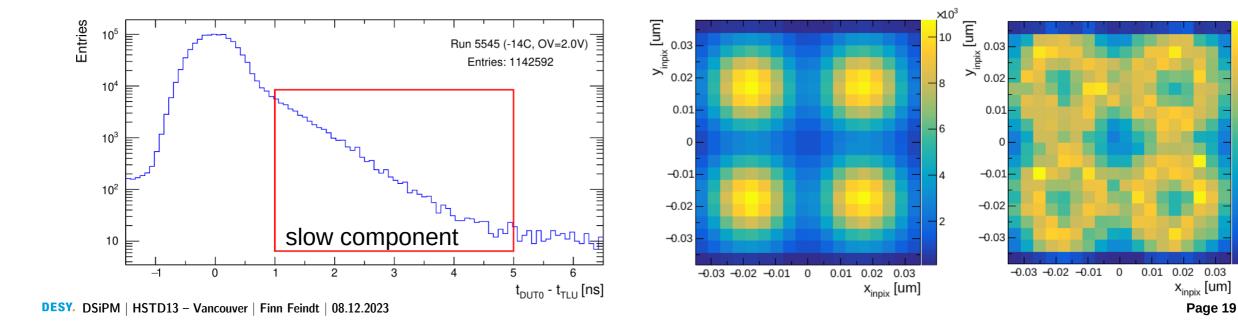
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20

Origin of the tails

- Left: Intercepts of tracks with associated hits
- Right: same, but only for slow component
- Slow response associated to SPAD edges





MIP Timing

Timing Plane Application

- Spatial and temporal resolution are promising
- Hit detection efficiency too low
 - 30 % fill factor probably not practical
- Fill factor can be optimized but will always be limited
- <u>F. Carnesecchi, et al.</u> increased MIP detection efficiency of SiPMs due to Cherenkov effect in encapsulation
 - We started studies in that direction!
 - Keep spatial resolution on the order of pitch
 - First photon counts \rightarrow suppress tails in timing
 - How much will the efficiency increase?
 - How much will it cost in material budget?





Example: encapsulated Hamamatsu SiPMs



Introduced a digital silicon photomultiplier produced in an LFoundry's 150-nm CMOS process

Test-beam characterization

- Hit detection efficiency (MIPs): > 30 %
- Spatial hit resolution (MIPs): \sim 20 um
- Temporal resolution (MIPs): \sim 50 ps

Submitted first paper on circuit design and laboratory characterization (already available on <u>ArXiv</u>)

We are eager to test dSiPM + radiator in the beam!

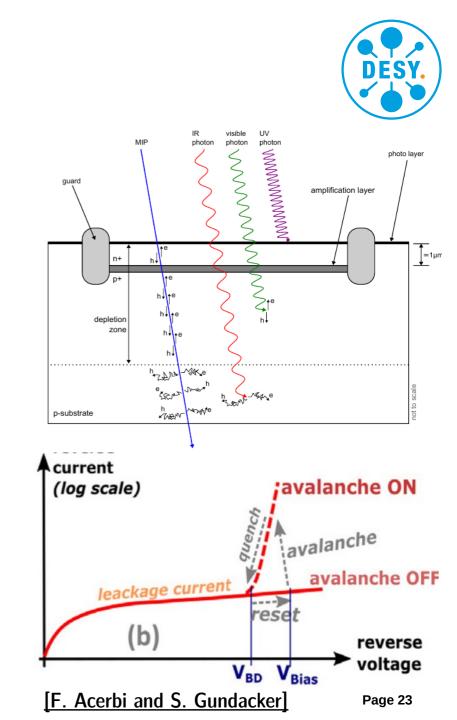




A Single Photon Avalanche Diode

Basic Building Block of a SiPM

- Strong doping gradient generates strong filed \rightarrow Geiger mode amplification
- Quenching of discharge by lowering the bias voltage (quenching resistor)
- Gain on the order of $10^{\scriptscriptstyle 5}$ to $10^{\scriptscriptstyle 6} \rightarrow$ counting device sensitive to single photons
- Photon interactions (optical energy range)
 - Exciting single electron from to conduction band
 - Penetration depth between 0.1 um (blue) and 10 (red) um
- Photon detection efficiency: fill factor x quantum efficiency x breakdown probability
- Electron interactions (GeV energy range, close to minimum)
 - 50 to 100 electron-hole pairs per micrometer
 - Deposition along electron trajectory

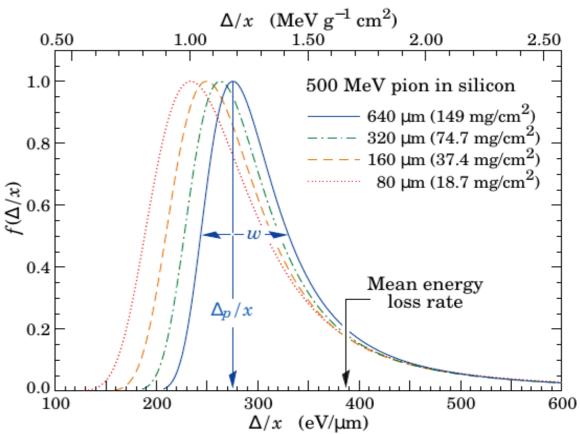


Charged Particles

And Their Interaction with Matter Silicon

- Electrons (GeV energy range, close to minimum)
 - Energy loss dominated by ionization and excitation
 - Radiative losses below 1 %, limited contribution to signal in thin Silicon detectors
 - Straggling functions are highly skewed due to rare large energy depositions
 - Mean ionization energy 3.67 eV per electron-hole pair
 - Signal on the order of 50 to 100 electron-hole pairs micrometer (depends on material thickens)
 - Deposition along electron trajectory
- Similar for other charged particles around energy loss minimum (MIPs)

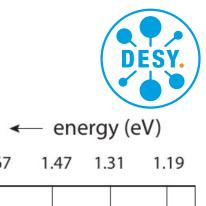


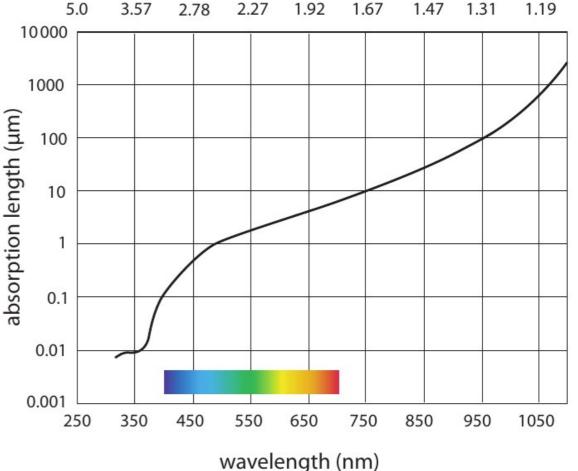


Optical Photons

And Their Interaction with Matter Silicon

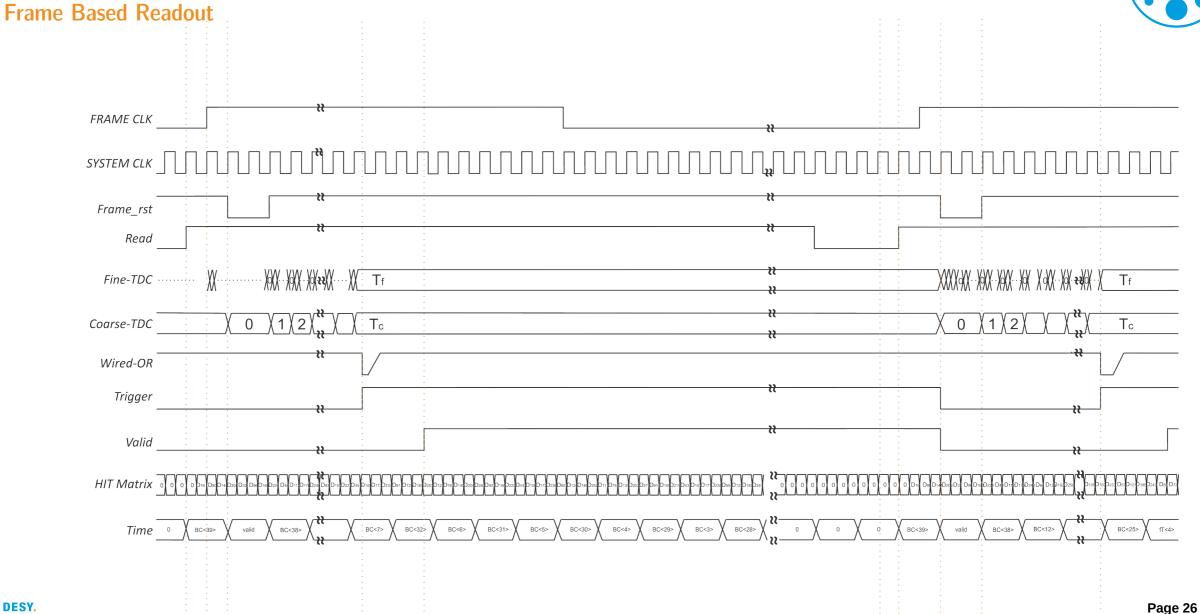
- Photons (optical energy range)
 - Internal photo effect: dominant contribution from 1 eV to several 10 keV [cw]
 - Exciting 1 electron from valance to conduction band
 - Minimal energy (band-gap) 1.12 eV, corresponding wavelength 1100 nm (UV)
 - Indirect band-gap transition requires phonon interaction
 - Strong rise in absorption probability to 3.4 eV
 - Temperature dependence
 - Penetration depth between 0.1 and 10 um





Timing Diagram

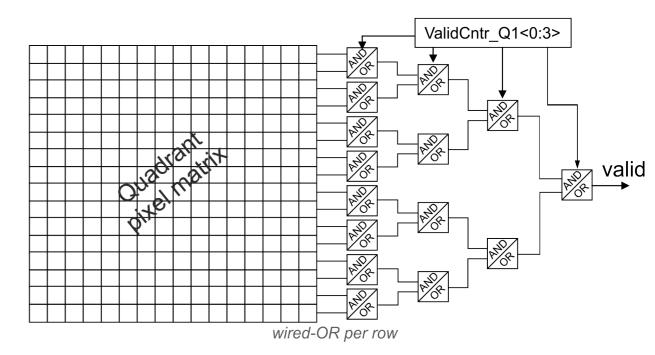




Validation Logic

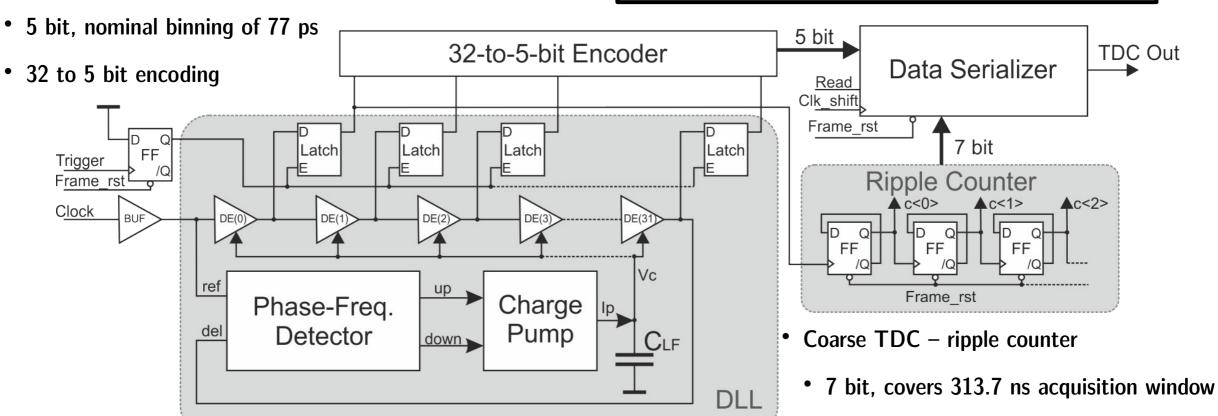
Suppressing Noise

- Implemented for each quadrant separately
- Hit within a row generates "true" for said row
- Cascade of AND/ OR operations between rows
- Allows to select certain hit patterns
 - E.g. at least 1 hit in each row
 - Or at least 1 hit per row in a pair of rows
- Helps to discard noise hits if certain signal patterns are expected





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- Fine TDC taped delay line with delay locked loop
 - ٠ 32 delay elements

Time Digital Converters

TDCs

٠

- Frame clock 3 MHz defines readout frames 333 ns
- System clock 408 MHz used in coarse and fine TDC

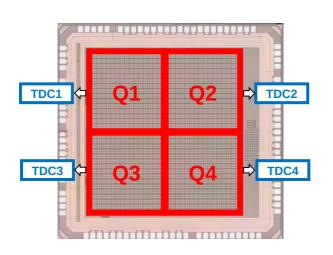


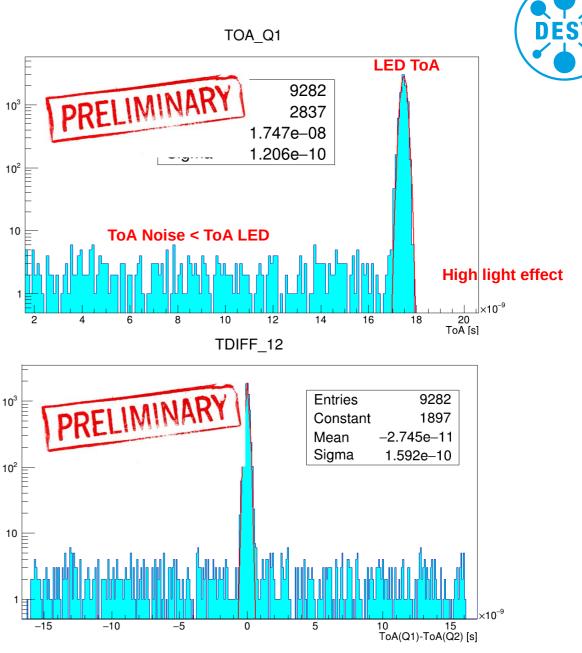
First Timing studies with LED

Preliminary Results

Timing performance

- From Preliminary LED studies
- TR of the whole system reported
- Quadrant TOA: $\pmb{\sigma}$ ~120 ps
- Time differences by Quadrants: σ ~160 ps
- No correction for propagation delays



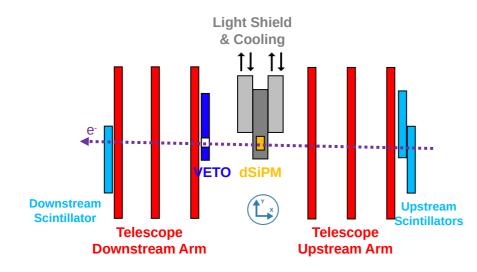


Our Setup

The First Shot

Setup in May 2022 – proof of concept, integration test

- Triggering using 3 scintillators in coincidence
 - 4th scintillator with hole vetoes tracks out of acceptance
- Track time resolution O(1ns) (scintillator + TLU TDC)
- Estimated track resolution around 5 um
- Temperature stabilization \sim 25° C (no cold box)



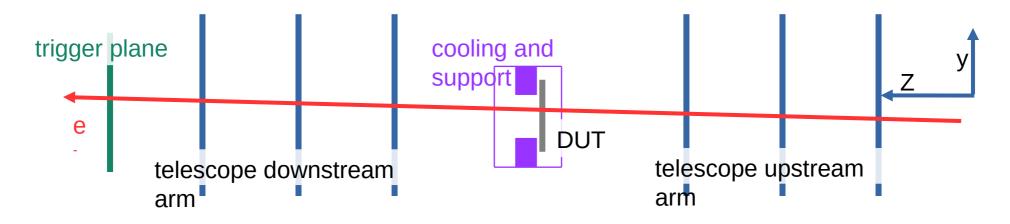




Beam Test – Introduction

DESY.

Test Bench for Particle Detectors – The Tracking Detector Case



Components

- Beam (DESY II 5 GeV, SPS, MAMI;)
- Tracking system, 6 planes of pixel detectors
- E.g. scintillators for timing and triggering
- Device Under Test

Goals

- Prove/ test integration of prototypes
- Performance characterization
 - Detection efficiency
 - Resolution in space, time, (energy)

Reconstruct individual charged particles – time and position information

Alignment

Material Budget Imaging

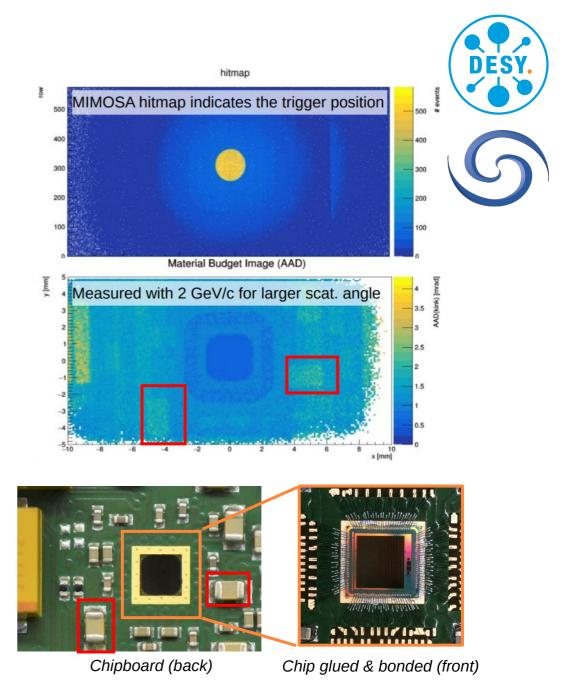
- DUT- Trigger Alignment With High Dark Count Rate
- DCR/MIP event distinction impossible before alignment
- dSiPM too noisy to use self trigger

Material Budget Imaging (MBI)

- Amount of scattering is proportional to the thickness of the scattering medium in radiation lengths
- Plot width of scattering angle distribution in DUT-plane

Evaluation of MB using Corryvreckan

- Maximize multiple Coulomb scattering
- Use the straight line approximation for tracks in the two arms of the beam telescope (TrackingMultiplet)
- Material budget image obtained in global coordinates





Contact

DESY. Deutsches Elektronen-Synchrotron

Finn Feindt Tangerine

www.desy.de

finn.feindt@desy.de